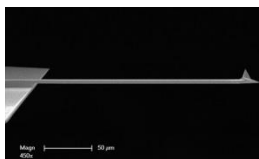
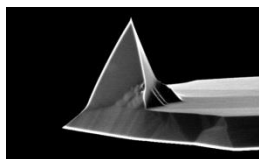
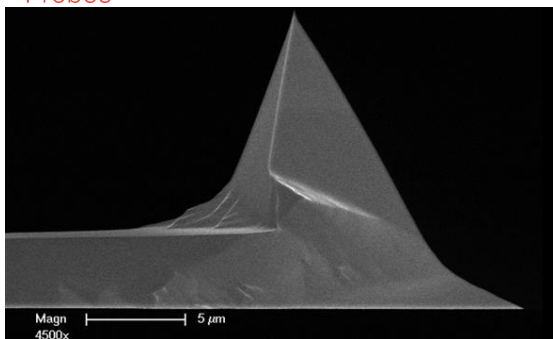


## NCLV

Tapping/Non-Contact,  
Long Cantilever AFM  
Probes



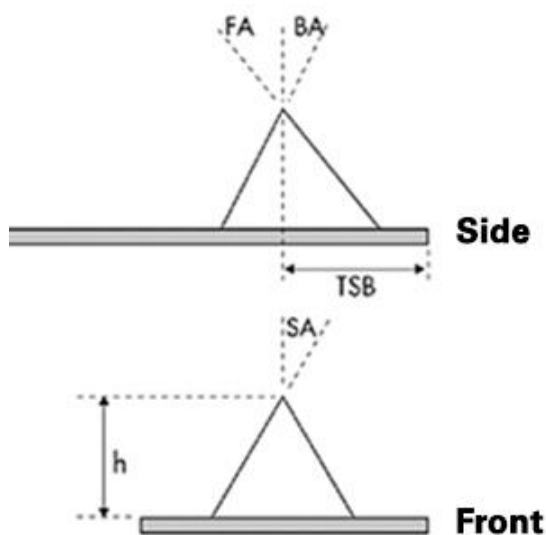
### Models

10-Pack  
No Reflex  
Coating

Wafer  
No Reflex  
Coating

10-Pack  
Al Reflex  
Coating

Wafer  
Al Reflex  
Coating



### Product Description

Value Line etched Silicon long-cantilever probes for imaging in TappingMode and non-contact mode in air.

**Specifications:** 48 N/m, 190 kHz, 10 nm tip radius, no reflex coating.

- 10 probes per pack.
- Compatible with most commercially available AFMs.

### Tip Specification

Geometry:	Standard (Steep)
Tip Height (h):	10 – 15 μm
Front Angle (FA):	25 ± 2.5°
Back Angle (BA):	15 ± 2.5°
Side Angle (SA):	22.5 ± 2.5°
Tip Radius (Nom):	10 nm
Tip Set Back (TSB)(Nom):	15 μm
Tip Set Back (TSB)(RNG):	5 - 25 μm

### Cantilever Specification

Material:	0.01 - 0.025 Ωcm Antimony (n) doped Si
Geometry:	Rectangular
Cantilevers Number:	1
Cantilever Thickness (Nom):	7 μm
Cantilever Thickness (RNG):	6.5 – 7.5 μm

For more information email:  
[afmprobeorders@bruker.com](mailto:afmprobeorders@bruker.com) or visit:

ValueAFMProbes.com